

EAST - [default.wsp:1]

File View Edit Tools Window Help

Drafts Pending Active

- L1: (139) ESD and 324/\$.ccls.
- L2: (1) 1 and (laser\$ adj beam\$)
- L3: (10) 1 and beam\$
- L4: (1) "5504438". PN.
- L5: (1) "5432461". PN.
- L6: (1) "5371459". PN.
- L7: (1) "5276400". PN.
- L9: (12) 8 and die\$ and beam\$
- L10: (10) 8 and laser\$
- L11: (9) 1 and laser\$
- L12: (12) "5432461"
- L13: (3) "6020746"
- L8: (47) electro\$ adj discharg\$ and 324/\$.ccls.**
- L14: (0) electro\$ adj discharg\$ and 324/752
- L15: (1) ESD and 324/752
- L16: (13) ESD and 324/750-755.ccls.
- L17: (52) ESD and 324/750-765.ccls.
- L19: (3) 17 and beam\$

Failed

- (0) ESD and 324/700-755.ccls.
- (0) \$
- (0) ESD and 324/750-775.ccls.

Saved

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UDC

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DBs USPAT Plurals Synonyms

Default operator: OR Highlight all hit terms initially

electro\$ adj discharg\$ and 324/\$.ccls.

	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current
1	<input type="checkbox"/>	<input type="checkbox"/>	US 6288554 B1	20010911	9	Method for inspecting hermetically sealed package	324/558	324/71.
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6252393 B1	20010626	9	System and method for normalizing and calibrating	324/202	324/232 ; 324/2
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6194904 B1	20010227	13	Socket test probe and method of making	324/754	
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6184623 B1	20010206	25	Method for controlling plasma-generating high	315/111.21	118/723 ; 118/7
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6177799 B1	20010123	15	Rechargeable battery electrode testing device	324/425	429/90
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6140928 A	20001031	22	Remaining battery capacity measuring device	340/636	320/134 ; 320/1
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6020744 A	20000201	18	Moisture sensor	324/678	324/664 ; 324/6
8	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5990698 A	19991123	7	Test method and apparatus for semiconductor element	324/766	324/551
9	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5892363 A	19990406	10	Electrostatic field measuring device based on	324/452	324/457 ; 324/7
10	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5847571 A	19981208	21	Membrane probing of circuits	324/754	324/757
11	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5841291 A	19981124	21	Exchangeable membrane probe testing of circuits	324/755	